

**Search Notes**

Application/Control No.

10/705,548

Examiner

Hieu Phan

Applicant(s)/Patent under  
Reexamination

LANG ET AL.

Art Unit

3738

**SEARCHED**

Class	Subclass	Date	Examiner
up date	search	10/28/05	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR